

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

---

In re application of: Mieher, et al.

Attorney Docket No.:  
KLA1P117X1D/1151/2

Application No.: 10/785,396

Examiner: Gordon J. Stock Jr.

Filed: February 23, 2004

Group: 2877

Title: APPARATUS AND METHODS FOR  
DETECTING OVERLAY ERRORS USING  
SCATTEROMETRY

---

Confirmation No. 6516

**AMENDMENT A**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

It is respectfully submitted that the Examiner enters the following amendments in response to the Office Action dated 20 October 2006, a response to which is due 20 January 2007.

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims that begin on page 5 of this paper.

**Remarks/Arguments** begin on page 13 of this paper.